New Insights into Se/BiVO₄ Heterostructure for Photoelectrochemical Water Splitting: A Combined Experimental and DFT Study

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ABSTRACT

Monoclinic clinobisvanite BiVO$_4$ is one of the most promising materials in the field of solar water splitting due to its band gap and suitable VBM position. We have carried out a comprehensive experimental and periodic density functional theory (DFT) simulations of BiVO$_4$ heterojunction with Selenium (Se/BiVO$_4$), to understand the nature of heterojunction. We have also investigated contribution of Se to higher performance by effecting morphology, light absorption and charge transfer properties in heterojunction. Electronic properties simulations of BiVO$_4$ shows that its VBM and CBM are comprised of O 2p and V 3d orbitals, respectively. The Se/BiVO$_4$ heterojunction has boosted the photocurrent density by three fold from 0.7 to 2.2 mAcm$^{-2}$ at 1.3 V vs. SCE. The electrochemical impedance and Mott-Schottky analysis consequence favorable charge transfer characteristics which account for the higher performance in Se/BiVO$_4$ compared to the BiVO$_4$ and Se. Finally, spectroscopic, photoelectrochemical and DFT evident that Se makes a direct Z-scheme (band alignments) with BiVO$_4$ where the photoexcited electron of BiVO$_4$ recombine with the VB of Se, consequences electron-hole separation at Se and BiVO$_4$, respectively as a result enhanced photocurrent is obtained.

1. Introduction
Hydrogen has long been identified as one of the most promising energy carriers,\textsuperscript{1} which can be easily obtained from renewable resources (water and sunlight) through photoelectrochemical (PEC) water splitting.\textsuperscript{1-3} The bottleneck in realizing the concept practically has been the difficulty in identifying stable low-cost semiconductors that meet the thermodynamic and kinetic criteria for photoelectrolysis of water.\textsuperscript{1} Suitable materials for PEC should be capable of absorbing maximum photons from visible spectrum of sunlight and function as an effective catalyst for water splitting. Therefore, the semiconductor (electrode) must have band structure with band edge position above and below the redox potential of water, low electron affinity, good photocorrosion stability and bandgap in the range of 1.8-2.2 eV for maximum solar to chemical energy conversion.\textsuperscript{4} Since the discovery of Fujishima and Honda,\textsuperscript{2} various semiconductors have been investigated to produce hydrogen as a solar fuel from water, using a visible spectrum of sunlight. However, development of suitable and sustainable semiconductor materials as efficient photoelectrode remains a challenge. A metal oxide such as TiO\textsubscript{2} has band edge positions that straddle the standard electrochemical potential of $E^\circ(H^+/H_2)$ and $E^\circ(O_2/H_2O)$, but its large band gap (absorb the UV part of the solar spectrum) accounts for 4\% of the solar irradiance. Although, CdS and CdSe having small band gap and suitable band edge positions but they are not stable under water photooxidation conditions.\textsuperscript{5,6} The stable semiconductors such as Fe\textsubscript{2}O\textsubscript{3}, WO\textsubscript{3}, and BiVO\textsubscript{4} have been explored for the water splitting application over the last few years.\textsuperscript{2,7-12} Among them, Fe\textsubscript{2}O\textsubscript{3} is the most widely studied material for H\textsubscript{2} production. However, the conduction band edge of Fe\textsubscript{2}O\textsubscript{3} is too low for spontaneous water photoreduction.\textsuperscript{13} As a result, complete water splitting with Fe\textsubscript{2}O\textsubscript{3} requires large external bias. While WO\textsubscript{3} having a band gap energy of 2.7 eV limits the theoretical solar-to-hydrogen (STH) efficiency to ca. 4.5\%.\textsuperscript{9} Recently, it has been found that monoclinic clinobisvanite BiVO\textsubscript{4} with an ideal band gap with 2.4 eV\textsuperscript{14} for water splitting\textsuperscript{15} as it can absorb as much as 11\% of the solar spectrum compared to that of the 4\% TiO\textsubscript{2}.\textsuperscript{16} However, BiVO\textsubscript{4}
usually shows a low photocatalytic activity owing to poor charge-transport characteristics\(^9\) and weak surface adsorption properties.\(^{17}\) In addition, many attempts have been made to improve the poor photocatalytic activity of BiVO\(_4\) due to its more positive potential in thermodynamic level.\(^{18}\) Coupling BiVO\(_4\) with an oxygen evolution catalyst such as cobalt-phosphate,\(^{18-21}\) iron oxyhydroxide\(^{22}\) and cobalt-borate\(^{23}\) is one of the options. Making a heterojunction between two dissimilar semiconductors is also an effective strategy to improve the electron-hole separation in BiVO\(_4\).\(^{2,7-12,18-21,24,25}\) Heterojunction has great benefit to PEC activities such as broadening the light absorption spectral, suppressing the charge recombination and enhancing charge separation.\(^{25}\) Representative heterojunctions or band alignments of binary dissimilar semiconductors are shown in Fig 1. Type-I heterojunction (Fig. 1a), an extensively studied PEC water splitting techniques where a narrow band gap semiconductor (Fe\(_2\)O\(_3\)) is combined with wide band gap semiconductor such as TiO\(_2\).\(^{26}\) In this combination, a complementary light absorption takes place and photocurrent improves by a consequence of facile electrons and hole transfer from the conduction and valence band of wide band gap semiconductor to small band gap material. In Type-II heterojunction (Fig. 1b), the relatively more negative potential (vs RHE) of the conduction and valence band of a narrow band gap of semiconductor (BiVO\(_4\)) is beneficial to enable the efficient charge transfer\(^{25}\) and high photocurrent density. Since the photo-excited electrons in BiVO\(_4\) where the conduction band is located at more negative potential can easily transfer an electron to the conduction band of WO\(_3\) that have the conduction band at positive potential (Fig. 1b), responsible for high photocurrent. And as a result, the holes from the valence band of WO\(_3\) can be transferred to the valence band of BiVO\(_4\) to oxidize H\(_2\)O and generate O\(_2\).\(^{10}\) In Type III heterojunction, both narrow band gap semiconductors (each having either an ideal VB or CB) are combined to efficiently perform the photoelectrochemical water splitting (Fig 1c). The photogenerated electron at the CB of FeS\(_2\) recombines with a hole at the VB of Sb\(_2\)Se\(_3\) and consequences separation of electron and
hole, responsible for high photocatalytic activity.²⁷ In Type IV band alignments (Fig d), electron-hole pairs separation occurs very easily due to the establishment of a direct Z-scheme in binary semiconductors. Since the photo-excited electrons at CB of wide band gap semiconductor (i.e., BiVO₄ or ZnO), located at more positive potential (vs RHE) would recombine with the holes of g-C₃N₄ that have the valence band at a more negative potential (Fig 1d). As a result of the aforementioned recombination, holes from the valence band of ZnO/BiVO₄ are transferred into the electrolyte to oxidize H₂O→O₂, whereas the electrons from the conduction band of g-C₃N₄ are transferred to the counter electrode which enhances the photocurrent.²⁸ Therefore, a proper band alignment of each semiconductor in all types of heterojunctions is necessary to develop a deeper understanding of the charge transport properties in water splitting process.

Figure 1: Schematic representation of different band alignments for high PEC performance.

The Type-I and II heterojunction are widely reported compared to Type III and IV, where BiVO₄ is mixed with other materials.⁹,²⁹,³⁰ From a thermodynamic point of view, the material used in place of g-C₃N₄ must have small band gap energy in case of Type IV heterojunction to favor the electrons excitation process. Graphitic carbon nitride; g-C₃N₄ (E₉ = 2.7 eV) and Silicon, Si (E₉ =1.1 eV) are the most popular visible light absorbing semiconductor to be paired in various metal oxide for PEC cells.³¹-³³ The more negative conduction band potential of g-C₃N₄ and Si compared to that of BiVO₄, facilitate the photogenerated electrons mobility to the external circuit due to high electron-hole pairs separation. Si-based materials are highly
efficient in the solar cell technology but they are too expensive to be used in PEC water splitting. The cost of a silicon wafer comprises the pure silicon cost, the crystallization cost, and the slicing cost.\textsuperscript{34} Also, the fabrication of the Si-based device is more complex as it requires proper handling of fairly fragile Si wafer. These factors lead to a motivation in developing Si-free PEC cell with a potentially good absorber material which can be prepared by easy growth techniques to reduce cost production and achieve high charge transport characteristics in the heterojunction (Type-IV heterojunction).

In this work, we demonstrate improved performance of a BiVO\textsubscript{4} (photoanode) through combining with an n-type Selenium (Se), to build band alignments as that of direct Z-scheme (Fig 1d). Se has been extensively studied as a photoabsorber in thin film devices such as solar cells, photocatalyst, xerography, and rectifiers.\textsuperscript{35-37} Due to its small band gap, it has high light absorption efficiency\textsuperscript{38} and can be combined with BiVO\textsubscript{4} to further improve the light harvesting ability. Moreover, Se has low surface states densities, large carrier lifetime\textsuperscript{39} and a high conductivity (1 x 10\textsuperscript{-3} Sm\textsuperscript{-1})\textsuperscript{40} which can affect the charge mobility. One disadvantage of Se is that it is more prone to photocorrosion by itself rather than their larger band gap counterparts. Therefore, when Se is coupled with a larger band gap semiconductor (in Type-IV heterojunction), the charge recombination of the photogenerated electron-hole pair can be reduced and also suppresses the Se layer photocorrosion. Since very limited information is available regarding Se-based PEC water splitting, hence, this work is a step forward to provide a new direction to replace a traditional visible-light photoabsorber \textit{i.e} Si with Se. The PEC performance of the Se/BiVO\textsubscript{4} heterojunction has been discussed to prove that Se is a promising material to be used as a high-performance visible light absorber in water splitting. Furthermore, periodic density functional (DFT) simulations are also carried out to countercheck the experimental data and elucidate the photocatalytic performance of Se, BiVO\textsubscript{4}, and Se/BiVO\textsubscript{4}. The fundamental electronic structure of the monoclinic clinobisvanite
BiVO$_4$ are rarely considered for the water splitting, so, its theoretical investigations along with experimental study might provide rational answers to comprehend the optical and electronic-relationship. Finally, these findings will be useful to get an insight to design an appropriate approach for improved PEC performance.

1. **Materials and Methods**

2.1. **Chemicals**

All commercial chemicals were purchased from sigma Aldrich and were used without any further purification. The chemicals used are bismuth nitrate pentahydrate, Bi(NO$_3$)$_3$.5H$_2$O, vanadium acetylacetonate, C$_{10}$H$_{14}$O$_5$V, sodium selenite, Na$_2$SeO$_3$, ethylene glycol, methanol, acetone, and isopropanol.

2.2. **Synthesis of Se/BiVO$_4$ photoanodes**

Conductive fluorine-doped tin oxides (FTO TEC 18 Ω/cm$^2$, Pilkington) coated glass were used as substrates. Before the deposition process, all substrates were cleaned with deionized water, followed by acetone and isopropanol for 15 minutes each, respectively in the ultrasonic bath and then dried. A potentiostat/galvanostat modulab solartron analytical was used for electrodeposition. A layer of Se was deposited galvanostatically at -20 mA vs. SCE for 90 seconds in an aqueous solution containing 50 mM Na$_2$SeO$_3$ with an FTO working electrode, SCE reference electrode, and platinum counter electrode. The as-prepared Se layer was rinsed with deionized water and dried. In next step, the BiVO$_4$ thin film was loaded on Se layer by aerosol-assisted chemical vapor deposition (AACVD). The BiVO$_4$ precursor solution was prepared by dissolving 0.2 M Bi(NO$_3$)$_3$.5H$_2$O in ethylene glycol and 0.2 M C$_{10}$H$_{14}$O$_5$V in methanol as reported in our previous work.$^{41}$ The precursor solution was poured into 20 ml round bottom flask which was converted to an aerosol by an ultrasonic dehumidifier and then transferred to the heated zone of a hot plate (where the Se coated FTO sample was placed). The deposition of BiVO$_4$ thin film was conducted for 90 minutes at ~450 °C in air.
2.3. Computational Methodology

First principle periodic DFT simulations are carried out with the help of Quantum ESPRESSO\textsuperscript{42} and the results were visualized with VESTA\textsuperscript{43} and virtual nano-lab (vnl 16).\textsuperscript{44} The experimentally available crystallographic file of the BiVO\textsubscript{4}; clinobisvanite structure is used as such which has Hall symmetry space group of -I 4ad with lattice parameters of $a = 5.147\,\text{Å}, b = 5.147\,\text{Å}, c = 11.7216\,\text{Å},$ and $\gamma = 90^\circ$.\textsuperscript{45} The bulk of Se with a space group of P3\textsubscript{2}1 having lattice parameters of $a = 4.355\,\text{Å}, b = 4.355\,\text{Å}, c = 4.949\,\text{Å}, \alpha = 90^\circ$ and $\gamma = 120^\circ$ is used for simulations. The exchange and correlation potential was treated by the Perdew-Zunger, spin-unpolarized local density approximation (LDA). As an input structure for calculations; the 24 atoms unit cell with $2\times2\times2$ supercell having [001] orientation and vacuum space of 10 Å, is taken into account for the periodic boundary condition (PBC) DFT simulations. Mostly, clinobisvanite monoclinic BiVO\textsubscript{4} exists in [001] orientation so, that is why the [001] orientation is opted for theoretical simulations to represent the experimental thin film.\textsuperscript{46} Moreover, the unreconstructed [001] termination possesses low surface energy and as a result represents the most probable surface termination.\textsuperscript{46} A $5\times5\times1$ Monkhorst-Pack $k$-grid and energy cutoff of 100 Ry is employed for the geometry relaxation and self-consistent (SCF) simulations of BiVO\textsubscript{4}; consisting of 96 atoms. The Broyden-Fletcher-Goldfarb-Shanno algorithm (BFGS) was used for the structural minimization.\textsuperscript{47} A $5\times5\times5$ Monkhorst-Pack $k$-grid with the same energy cutoff is used for the non-SCF part to get the density of states (DOS) and partial DOS (PDOS). The band structure simulations were performed along the direction of $\Gamma, Z, R, X,$ and $M$ of the Brillouin zone sampling. The valence electron configurations considered are: $5d^{10}\,6s^2\,6p^3$ for Bi; $3p^6\,3d^3\,4s^2$ for V; $2s^2\,2p^4$ for O, and $4s^2\,4p^4\,3d^{10}$ for Se atom.

2.4. Characterizations
X-ray diffraction (XRD) measurements were conducted using a (Bruker D8 Advance diffractometer) in the 2θ range from 20° to 60°. The morphologies and elemental mapping of the films were examined by field emission scanning microscopy (FESEM) and energy dispersive X-ray spectroscopy (EDX) on an (FE-SEM SUPRA VP55). Optical characterizations were conducted by a UV-Vis absorption spectrophotometer Perkin Elmer Lambda 950). The PEC measurements were recorded using a potentiostat/galvanostat Autolab PGSTAT 204, connected to the three-electrode configuration in a 0.5 M Na₂SO₄ electrolyte, an SCE (saturated KCl) as the reference electrode and a platinum as the counter electrode in a quartz cell. The chronoamperometry curves of the electrodes were obtained at 0.50 V vs. SCE. Electrochemical impedance spectroscopy (EIS) and Nyquist plot were performed using the same experimental setup as the PEC measurements. The frequency was 100 kHz-100 mHz with 0.5 V applied bias under dark and simulated light conditions (light intensity of 100 mWcm⁻²). The illuminated area was 1.0 cm² for all experiments and the observed spectra were fitted by using GPES software.

3. Results and discussion

3.1. Structural analysis

The structural phase and purity of the as-synthesized BiVO₄ and Se/BiVO₄ films are shown in Fig. 2. All the diffraction peaks of Se/BiVO₄ were identified to have a monoclinic clinobisvanite BiVO₄ which has good agreement with standard JCPDS pattern (00-014-0688). The peaks exhibited from Se thin film was appeared to have a monoclinic Se (JCPDS No. 00-054-0500) (Fig. S1). No impurity phases are observed, which confirms the purity of deposited films. The narrow and sharp peaks from the XRD patterns of all samples indicate high crystalline nature of the films. The peaks of BiVO₄ can clearly be seen at 2θ = 28.82°, 30.55°, 34.50°, 35.22°, 39.78°, 42.47°, 46.71°, 47.31°, 50.32° and 53.25° which assigned to the planes of (-121), (040), (200), (002), (211), (051), (240), (042), (202) and (-161) respectively.
These BiVO₄ peaks are clearly visible in Se/BiVO₄ thin film followed by a small intensity Se peak at (122) while the rest of Se peaks are diminished due to the growth of BiVO₄ on top of Se. Meanwhile, the deposition of BiVO₄ to form a heterojunction does not cause any changes in the crystal structure of Se and other electronic properties. The crystallite size calculated based on t peaks at (122) for Se and (-121) for BiVO₄ in Se/BiVO₄ are 838.1 and 369.1 Å, respectively (Fig 2).

![X-ray diffraction patterns](image)

**Figure 2:** X-ray diffraction patterns of a) BiVO₄ and b) Se/BiVO₄.

### 3.2. Morphology

Surface morphology of Se, BiVO₄, and Se/BiVO₄ thin films are characterised by FESEM analysis which is presented in Fig. 3. The surface morphology of Se film have a dense sponge-like surface with particles diameter in the range of 217-392 nm on average and film thickness is 368 nm (Fig. 3d). The morphology of BiVO₄ (Fig. 3b) comprised of a spherical particle bumpy surface with an average particle size and thickness (Fig. 3e) of about 357–680 nm and 570 nm, respectively. The FESEM images of Se/BiVO₄ films showed a nanoporous structure with particles size smaller than that of Se and BiVO₄ as shown in Fig. 3c. The porous structure beneficial to improve the electrode/electrolyte interfacial area which ultimately increases the movement of the photogenerated charge carriers and reduces the charge recombination rate during the photo-oxidation reactions. The reduction in particle size is consistent with the reduction of the grain size obtained from XRD. The film thickness of Se/BiVO₄ is increased
to ~758 nm (Fig. 3f). It is observed that the morphology of Se is denser than that of BiVO₄. This feature is suitable for BiVO₄ to be deposited on top of the Se layer or in contact with the electrolyte in the heterojunction structure to increase the electrolyte/photoelectrode interfacial area (Fig. 4a).⁴⁹ The Se layer is placed on top of the BiVO₄ (forming BiVO₄/Se heterojunction), along with compact morphology of Se which may obstruct direct contact in BiVO₄ layer into the electrolyte, the smaller band gap Se will also hinder light penetration to BiVO₄ as well as Se is more prone photocorrosion. (Fig. 4b). As a result, this may not only limit the catalytic reaction but also block some of the light penetration to the BiVO₄ film. A similar case is observed in CdS/BiVO₄ electrode by Jiang et al.⁴⁹ where they compared the influence of the light absorption on CdS/BiVO₄ and BiVO₄/CdS structures. In addition, the purity and elemental presence of the constituents in the heterojunction (Se/BiVO₄) electrode is confirmed through EDX and elemental mapping (Fig. 3g and h). The EDX spectrum shows strong peaks for the Bi, V, O and low level for the Se, while the rest of them are belong to the FTO.
Figure 3: FESEM images and thickness of Se (a) and (d), BiVO₄ (b) and (e) and Se/BiVO₄ (c) and (f). The EDX spectrum (g) and Elemental mapping (h) of Se/BiVO₄, (i) the Se, BiVO₄ and Se/BiVO₄ samples.

![Image](image_url)

Figure 4: Schematic diagram of a) Se/BiVO₄ and b) BiVO₄/Se surface structures.

3.3. AFM

The 3D AFM images and surface roughness of Se, BiVO₄, and Se/BiVO₄ films are shown in Fig. 5 and Table 1. As expected, Se/BiVO₄ film showed high surface roughness compared to that Se and BiVO₄ films which may be due to the formation of dual layers and thicker films in the heterojunction (Se/BiVO₄). Generally, high surface roughness and small grain size can significantly affect the PEC performance as more sites are exposed for the photocatalytic reactions. Moreover, it is believed that films with rough surface enhances the light scattering and improve the light absorption capability.

![Image](image_url)

Figure 5: AFM images of (a) Se, (b) BiVO₄ and (c) Se/BiVO₄.
Table 1: The surface roughness of Se, BiVO₄, and Se/BiVO₄ thin film photoanodes.

<table>
<thead>
<tr>
<th>Sample</th>
<th>Surface roughness (nm)</th>
</tr>
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<tbody>
<tr>
<td>Se</td>
<td>32.71</td>
</tr>
<tr>
<td>BiVO₄</td>
<td>42.85</td>
</tr>
<tr>
<td>Se/BiVO₄</td>
<td>77.80</td>
</tr>
</tbody>
</table>

3.4. Optical properties

The optical absorption spectra of these films are presented in Fig. 6a, where the low absorption intensity of Se electrode is attributed due to its low thickness. As can be seen in Fig. 3d, the substrate is not fully covered by Se particles and in some part of the electrode, the FTO substrate can clearly be seen, responsible for the light scattering from FTO compared to Se. The absorption intensity of Se/BiVO₄ slightly enhanced to shorter wavelength when BiVO₄ layer was coated on Se. This enhancement is because of the high absorption intensity of the BiVO₄ film, light scattering of porous, rougher surface and thicker film of Se/BiVO₄ electrode. Moreover, the Se/BiVO₄ thin film is dark yellowish which is almost similar to BiVO₄ electrode (see samples shown in Fig. 3i) which suggests that most of the light is absorbed by BiVO₄ layer in the heterojunction (Se/BiVO₄). Therefore, the Se/BiVO₄ thin film electrode is more blue-shifted at a wavelength of ~ 470-500 nm (BiVO₄=2.43 eV) compared to ~ 700 nm (Se=1.74 eV). Due to these factors, Se/BiVO₄ electrode absorbs more visible light than that of either Se or BiVO₄. The optical band gap is calculated according to equation 1.⁵¹

\[(αhv)^n = A (hv-E_g)\]  

(1)

Where \(α\) is the absorption coefficient, \(ν\) is the incident light frequency \(E_g\) is the band gap and \(A\) is constant. \(n\) depends on the characteristic of the transition in a semiconductor; for a direct transition, \(n = 2\). The optical band gaps are evaluated from the relation of \((αhv)^2\) vs. photo energy \((hv)\). The extrapolations of the Tauc plots on \(x\)-intercept give the optical band gap of 2.43 eV for BiVO₄ (Fig. S2)⁴¹ and 1.74 eV for Se (Fig. 6) which is also consistent with the recently reported work of Wang et. al.⁵²
3.5. DFT Simulated Electronic and Optical Properties of BiVO4

Basically, BiVO4 exists in three different crystalline polymorphs; orthorhombic pucherite, tetragonal dreyerite, and monoclinic clinobisvanite.\textsuperscript{53} The photocatalytic activity and surface reaction is highly dependent on phase and crystal orientation of semiconductor oxide.\textsuperscript{54-56} For instance, the tetragonal BiVO4 possesses a band gap of 2.9 eV and mainly absorbs UV light, while the monoclinic clinobisvanite phase exhibits a much higher photocatalytic activity due to its favourable band gap (2.4–2.5 eV) in the visible region of the electromagnetic spectrum (shows both visible light and UV absorption), and a valence band position suitable for driving water oxidation under illumination.\textsuperscript{57}

![Figure 6: a) UV-vis absorption spectra of the Se, BiVO4 and Se/BiVO4. Tauc plot of b) Se and c) Se/BiVO4 thin films.](image)

**Figure 6.** a) UV-vis absorption spectra of the Se, BiVO4 and Se/BiVO4. Tauc plot of b) Se and c) Se/BiVO4 thin films.
The XRD analysis of our fabricated BiVO$_4$ films prove the formation of monoclinic clinobisvanite BiVO$_4$, so, that is why we have considered the same structure to investigate its theoretical insight. In order to correlate the experimental thin film properties, the [001] phase (generally, the more stable) is employed for simulations (Fig. 7).

Moreover, to analyze the electronic properties such as DOS/PDOS, band structure, the position of the valence band (VB) and conduction band (CB) are calculated from the optimized crystal structures. The DOS of BiVO$_4$(001) is simulated to find out its band gap and edge positions which are given in Fig. 8. The simulated band gap of BiVO$_4$-001 is 2.25 eV which underestimate our experimental band gap (2.43 eV) to about 0.18 eV. This slight underestimation of the band gap is expected from LDA method of DFT calculation.$^{58}$

**Figure 8:** Total density of states of BiVO$_4$(001), the Fermi level is set to zero

In order to find the atomic and orbital contribution to form, valence, and conduction bands; the PDOS are simulated (Fig 9). In Fig. 9(a) the PDOS of BiVO$_4$(001) is shown, where the O atoms are responsible for the developing of valence band edge, however, the conduction band edge is populated by the atomic contribution of V atoms. Further details of the s, p, and d orbital contribution of Bi, V, and O are depicted in Fig. 9b-d. The PDOS of Bi atoms show that s
orbitals are involved in making the valence band edge of Bi while its p orbitals are situated in the conduction band edge. Both the valence and conduction bands of V atoms prominently consist of its 3d orbitals while in case of O, 2p orbitals have a major role in developing their band edge positions.

![Diagrams](image)

**Figure 9:** PDOS of BiVO₄(001) (a), Bi (b), V (c), and O (d); Fermi level is set to zero.

The valence band electronic structure of BiVO₄(001) spread over in the range of -0.65 to -19 eV, can be distinguished into three major parts (*vide infra*). The upper portion of the region from -0.65 eV to -6 eV is clearly dominated by the 2p orbitals of O, while its lower portion is partially hybridized by the d and s orbitals of V and Bi, respectively. The middle portion (-9 to -11 eV) of the valence band is equally occupied by sp of O, p d of V and sp orbitals of Bi. The region from -16 to -19 eV of the valence band is majorly contributed from the s orbital of O and its lower part is constituted from the hybridized s, p, and d orbitals of Bi and V atoms.
These orbitals have a major role in the developments of charge carriers and their effective masses.

![Figure 10](image)

**Figure 10**: Valence and Conduction DOS of BiVO₄(001), Fermi level is set to zero

The conduction-band electronic structure is situated in the range of 1.60 to 4.4 eV, where the CBM is occupied by the d orbitals of V with the contribution of the p orbitals of Bi. The major portion of the unoccupied state within the conduction band of BiVO₄ is almost equally populated through the mutual hybridization of Bi p and V d orbitals. From Fig. 10, we can see that the anti-bonding orbitals of d and p of V and O are responsible for the effective masses of the electrons.

Band structure of the BiVO₄(001) along the k-points direction of Γ, Z, R, X, and M is given in Fig. 11. An indirect band gap of 2.25 eV is simulated which is in good agreement with the experimental and recently theoretical reported data. Furthermore, this indirect band gap is due to the electronic excitation from the X→Γ, as clearly shown Fig. 11. Generally, in case of indirect band gap, the band edges are not aligned thus, the electron does not transit directly to the conduction band. In this process, both a photon and a phonon are involved. That is why a new concept of the mixed phases of the BiVO₄ is reported which can efficiently perform the water splitting. At the Fermi energy of -5.73 eV, the vacuum phase VBM and CBM are ca. -6.38 and -4.13 eV, respectively. These simulated band edge energies indicate that BiVO₄ can be used as a photocatalytic material for redox reactions, such as water splitting but need
modification for high PEC performance. This statement clearly corroborates our photocatalytic activity (*vide infra*). The effective masses of the photogenerated electrons ($m_e^*$) and holes ($m_h^*$) along the $X\rightarrow\Gamma$ directions of k-points are calculated by fitting parabolic approximation around the bottom of the CBM or the top of the VBM, respectively; using equation 2 (Table 2):

$$m^* = \frac{\hbar^2}{d^2 \frac{dE}{dk^2}}$$  \hspace{1cm} (2)

where $\hbar$ is the reduced Planck constant, $E$ is the energy of an electron at wave vector $k$ in the same band (VBM or CBM). To acquire the validity of the parabolic approximation within the specified space, the region for parabolic fitting is controlled by an energy difference of 1 meV along a particular direction around the VBM or CBM.

**Table 2:** Band gap and effective masses of photogenerated electrons and holes, estimated from the calculated band structure along the suitable direction.

<table>
<thead>
<tr>
<th>Experimental</th>
<th>Theoretical</th>
<th>Direction in Brillouin zone</th>
<th>$m_e^*/m_0$</th>
<th>$m_h^*/m_0$</th>
<th>Band gap</th>
</tr>
</thead>
<tbody>
<tr>
<td>BiVO$_4$ (Film)</td>
<td>BiVO$_4$(001)</td>
<td>Indirect</td>
<td></td>
<td></td>
<td>2.43</td>
</tr>
<tr>
<td>Se Bulk</td>
<td></td>
<td>$X\rightarrow\Gamma$</td>
<td>1.93</td>
<td>0.45</td>
<td>2.25</td>
</tr>
<tr>
<td>Se Bulk</td>
<td></td>
<td>Direct</td>
<td></td>
<td></td>
<td>1.74</td>
</tr>
<tr>
<td>Se Bulk</td>
<td></td>
<td>$\Gamma\rightarrow\Gamma$</td>
<td></td>
<td></td>
<td>1.60</td>
</tr>
</tbody>
</table>

The effective masses of electrons and holes of the BiVO$_4$(001) is calculated from the band structure as these photogenerated electrons and holes thermally relax to the bottom of the conduction band and the top of the valence band, respectively. The simulated values of the effective masses of photogenerated electrons and holes of the BiVO$_4$(001) slab are 0.45 and 1.93 $m_e$, respectively. Lighter mass of charge carriers the faster will be their movements at the interface.$^{60,61}$ Moreover, larger the difference between the effective mass of electron and hole the lower will their charge recombination. The lower photocatalytic activity of the
BiVO$_4$(001) is because of their heavy charge carriers. Our experimental results also support this theoretical observation.

Figure 11: Band Structure of the BiVO$_4$ along the [001] direction; the Fermi level is set to zero.

The band structure of Se bulk along with its crystal structure is given in Fig 12, where the simulated band gap of 1.60 eV in the $\Gamma$→ $\Gamma$ direction of the Brillouin zone has a nice correlation with our experimental observed of 1.74 eV. The vacuum simulated VBM and CBM of the Se bulk are ca. -5.08 and -3.48 eV, respectively at the Fermi energy of 4.22 eV.

Figure 12. Band structure of the Se bulk, where the Fermi energy is set to zero.
As shown in Fig 13, the Se/BiVO₄ form a direct Z-scheme like heterojunction, where the enhanced photocurrent activities are because of Se layer. When light shines on Se/BiVO₄ heterostructure, the photogenerated electron of BiVO₄ in its CB recombine with a hole at VB of Se, consequences free electrons and at CB of Se case substential increase in photocurrent as observed experimentally. This electron/hole recombination and separation create a direct Z-scheme like structure where the free electron at negative potential (CB) of Se is responsible for the enhancement of photocurrent (Fig 13).

Figure 13. Energy level diagram of the simulated Se-bulk and BiVO₄(001)

3.6. Photoelectrochemical properties

The results of photocurrent density measurements are presented in Fig. 14 which is also compared with our previous work.⁴¹ The photocurrent density obtained by the samples increase with increasing applied voltage. All samples of Se, BiVO₄, and Se/BiVO₄ show very good response under illumination and represent anodic photocurrent patterns which indicate that these electrodes have n-type semiconductor behavior. Moreover, the chopped photocurrent density-voltage is shown in Fig. 14b led us to conclude that Se/BiVO₄ photoanode is photocatalytically active under illumination. The photocurrent density of Se/BiVO₄ increased up to 2.2 mAcm⁻² at 1.3 V vs. SCE, much better than that of Se and BiVO₄. This enhanced photocurrent-density proves that Se could potentially be used in water splitting application as
an efficient complementary light absorbing layer with other metal oxides. This photocurrent enhancement might also be attributed to better charge transfer in heterojunction as well as reduction of the grains and particles size, observed from XRD and FESEM analysis. In general, the small grain and particle size enlarge the surface area for reaction. Hence, more surface area is exposed to the electrode/electrolyte interface which further promotes the photocatalytic process. Moreover, the porous structure of the Se/BiVO₄ film also widen the contact area between Se/BiVO₄ photoanode and electrolyte. This feature provides more surface sites for reaction, reducing charge transport distance and increase the accumulation of photogenerated electrons.⁶²-⁶⁵

![Graph](image)

**Figure 14:** Photocurrent density of a) Se and (b) Se/BiVO₄ photoanodes under dark and light intensity of 100 mWcm⁻² in 0.5 M Na₂SO₄.

To further support the PEC enhancement of Se/BiVO₄, EIS measurement was carried out. Fig 15a shows the Nyquist plots of BiVO₄ and Se/BiVO₄, measured in 0.5 M Na₂SO₄ at 100 kHz to 0.1 Hz in the presence and absence of light (100 mWcm⁻²) and 0.5 V applied potential vs. SCE. It can be seen that the diameter of curves diminished when the fabricated layers were exposed to light. The diameter of curves is a function of overall charge transfer through the electrodes. To quantify the charge transfer resistance, the EIS data were fitted to the equivalent circuit shown in the Fig. 15b. The equivalent electrical circuit consists of two relaxation times, dark and light condition. As observed in Fig. 15a, both loops in the equivalent circuit are in a
parallel configuration. The corresponding loop of the semiconductor \((R_{SC} \parallel CPE_{SC})\) is in series with the interfacial resistance of the double layer/thin film \((R_{dl})\) and both of them are in parallel with the double layer capacitance \((C_{dl})\). For a more accurate representation of the capacitance behavior, the constant phase element (CPE) is used instead of a pure capacitor in the simulations. The impedance of a CPE \((Z_{CPE})\) for a non-ideal circuit element is given in equation 3:

\[
Z_{CPE} = \frac{1}{Q(j2\pi f)^n}
\]  
(3)

Where \(f\) is applied frequency, \(j\) is imaginary number, \(Q = C\) if the exponent \(n=1\), and \(Q \neq C\) if exponent \(1 > n > 0\). It must be noted that the capacitance behavior is approximated by \(Q\), if the electrode surface is rough or when the dielectric property of the electrode components is heterogeneous.\(^6^6\) The detailed corresponding electro-kinetic elements for the samples are tabulated in Table 3. It is found that the charge transfers resistance of the semiconductor \((R_{SC})\) is in the order of \(\text{BiVO}_4 > \text{Se/BiVO}_4\) in both light and dark conditions. The photocurrent-voltage curve (Fig. 14b) correlates with the EIS results. The smaller value of \(R_{SC}\) represents improved charge transport characteristics which provide favorable environment PEC reactions.\(^6^7\)

![Figure 15: a) The Nyquist plots and b) equivalent circuit of BiVO₄ and Se/BiVO₄ photoanodes.](image-url)
Table 3: The EIS parameters from the simulation of the equivalent circuit model at 0.5 V vs. SCE.

<table>
<thead>
<tr>
<th>Electrode</th>
<th>$R_s$ ($\Omega$)</th>
<th>$R_{dl}$ (k$\Omega$)</th>
<th>$C$ ($\mu$F)</th>
<th>$R_{SC}$ (k$\Omega$)</th>
<th>$Q (Y_o)$ (Mho)</th>
<th>$n$</th>
</tr>
</thead>
<tbody>
<tr>
<td>BiVO$_4$(L)</td>
<td>15.50</td>
<td>1.91</td>
<td>18.70</td>
<td>5.56</td>
<td>33.81</td>
<td>0.62</td>
</tr>
<tr>
<td>BiVO$_4$(D)</td>
<td>21.90</td>
<td>47.44</td>
<td>14.02</td>
<td>97.74</td>
<td>30.30</td>
<td>0.83</td>
</tr>
<tr>
<td>Se/BiVO$_4$(L)</td>
<td>26.30</td>
<td>5.93</td>
<td>120.60</td>
<td>2.24</td>
<td>717.00</td>
<td>0.84</td>
</tr>
<tr>
<td>Se/BiVO$_4$(D)</td>
<td>24.60</td>
<td>1.81</td>
<td>164.40</td>
<td>18.25</td>
<td>148.50</td>
<td>0.88</td>
</tr>
</tbody>
</table>

Figure S3 illustrates stability of Se/BiVO$_4$ electrode under chopped irradiation at 0.5 V vs. SCE in 0.5 M Na$_2$SO$_4$ with interval of 5 seconds. This potential was chosen because the photoelectrode has started to show response to the light at ~ 0.40 V. As noted in the figure, the photocurrent of the BiVO$_4$ film is gradually decreased with increasing illumination time, indicating the accumulation of the photo-generated holes at the surface of BiVO$_4$ due to poor kinetics charge transfer. However, the photocurrent value of 0.15 mAcm$^{-2}$ remains constant for 40 minutes for Se/BiVO$_4$. This constant photocurrent value confirms the photo-stability of the heterojunction film which can suggest that the Se is rather effective for improving the steady state PEC performance of BiVO$_4$ electrode. In the chopped stability plot, photocurrent spikes are observed, which indicate recombination. When the light is turned on, a sharp positive photocurrent spike is seen (which is termed the instantaneous hole current) which then decays to a steady state current after recombination of the holes with electrons.$^{69}$

Figure 16a and b show the Mott-Schottky plot of Se and BiVO$_4$ electrodes that were measured in 0.5 M Na$_2$SO$_4$ electrolyte without illumination. The positive gradients of Mott-Schottky plots indicate the n-type semiconducting nature in which electrons are the majority charge carriers. The flat band potential, ($E_{fb}$) of Se electrode is estimated to be -0.17 V vs. SCE or equal to 0.074 V vs. NHE while, the $E_{fb}$ of BiVO$_4$ is 0.33 V vs. SCE (0.57 V vs. NHE). At vacuum level, the CBM of Se is ca. -4.51 eV while that of BiVO$_4$ is -5.01 eV. By taking the
$E_g$ of the Se electrode from Fig. 6b), the alignment of the energy levels for heterojunction Se/BiVO$_4$ can thus be drawn in Fig. 16c). Clearly, the valence band of Se is 1.814 V vs. NHE (-6.25 eV at vacuum). In a dual-absorber system (complementary absorption of UV-vis), electrons in both Se and BiVO$_4$ are excited upon illumination. It can be further concluded that most of the incidents light permeated through the BiVO$_4$ layer are absorbed by Se film. Due to the more negative potential of the conduction band of Se, photo-electrons at the conduction band of BiVO$_4$ recombined with holes at valence band of Se, which reduce the recombination of photogenerated electron-hole pairs by Se itself. This process generates more photocurrent since photo-generated electrons in the conduction band of Se are impeded to recombine with its holes. Note that, the high absorption intensity of Se/BiVO$_4$ electrode means more electron-hole pairs generation (Fig. 6a), does not contribute to the photo-oxidation process due to the thermodynamically forbidden hole transfer from Se to BiVO$_4$ (valence band Se located at more negative potential than valence band BiVO$_4$). However, this type of heterojunction had served as a center of charge recombination between holes in the valence band of Se and electrons from the conduction band of BiVO$_4$. As a result, this facilitates the accumulation of photo-generated electrons in Se to the external circuit and generates high photocurrent. This type of heterojunction was said to have more efficient charge separation and photocatalytic activities.$^{68}$
**Figure 16:** Mott-Schottky plots of a) Se and b) BiVO₄; c) the alignment of the energy levels of heterojunction Se/BiVO₄.

**Conclusion**

We have successfully fabricated a direct Z-scheme like heterojunction of Se and BiVO₄ (Se/BiVO₄), as a thin film for the improved PEC performance. The thin film photoanode are fully characterised by XRD, SEM, EDX, UV-Vis band gap calculations, PEC and electrochemical activity. Moreover, we also proposed band structure diagram for our heterojunction which is counterchecked by solid state theoretical simulations. The as-prepared Se and BiVO₄ exhibit monoclinic and monoclinic clinobisvanite structures, respectively and have low photocatalytic activities. An enhanced PEC activity is observed in case of heterojunction, compared to their individual constituents (Se and BiVO₄). Density functional theory (DFT) simulations are carried out for the BiVO₄ and Se to simulate their band gap, and band edge positions in the proposed heterojunction band diagram. The PEC properties of Se/BiVO₄ indicate that the increment in performance is due to the presence of Se layer which acts as a hole trapping agent, light absorber, and improves the charge separation in the resulted film. The Se/BiVO₄ has 1.5 times higher photocurrent density than that of BiVO₄ due to higher surface area, small grain size, high roughness, efficient charge separation and minimum charge recombination rate. Moreover, the existence of dual absorption layers of Se and BiVO₄ significantly increased the light absorption which has ultimately promoted more charge generation. The results prove that Se/BiVO₄ heterostructure is a potential candidate for PEC water splitting, confirmed by DFT simulations.

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References


